

June 1997 Revised December 2000

GTLP16617 17-Bit TTL/GTLP Synchronous Bus Transceiver with Buffered Clock

General Description

The GTLP16617 is a 17-bit registered synchronous bus transceiver that provides TTL to GTLP signal level translation. It allows for transparent, latched and clocked modes of data flow and provides a buffered GTLP (CLKOUT) clock output from the TTL CLKAB. The device provides a high speed interface between cards operating at TTL logic levels and a backplane operating at GTLP logic levels. High speed backplane operation is a direct result of GTLP's reduced output swing (<1V), reduced input threshold levels and output edge rate control. The edge rate control minimizes bus settling time. GTLP is a Fairchild Semiconductor derivative of the Gunning Transceiver logic (GTL) JEDEC standard JESD8-3.

Fairchild's GTLP has internal edge-rate control and is process, voltage, and temperature (PVT) compensated. Its function is similar to BTL and GTL but with different output levels and receiver threshold. GTLP output LOW level is typically less than 0.5V, the output level HIGH is 1.5V and the receiver threshold is 1.0V.

Features

- Bidirectional interface between GTLP and TTL logic levels
- Designed with edge rate control circuitry to reduce output noise on the GTLP port
- V_{REF} pin provides external supply reference voltage for receiver threshold adjustibility
- Special PVT compensation circuitry to provide consistent performance over variations of process, supply voltage and temperature
- TTL compatible driver and control inputs
- Designed using Fairchild advanced CMOS technology
- Bushold data inputs on the A port eliminates the need for external pull-up resistors on unused inputs.
- Power up/down and power off high impedance for live insertion
- 5 V tolerant inputs and outputs on the LVTTL port
- Open drain on GTLP to support wired-or connection
- Flow through pinout optimizes PCB layout
- D-type flip-flop, latch and transparent data paths
- A Port source/sink -32 mA/+32 mA
- GTLP Buffered CLKAB signal available (CLKOUT)

Ordering Code:

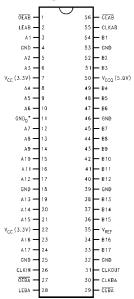
Order Number	Package Number	Package Description
GTLP16617MEA	MS56A	56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300 Wide
GTLP16617MTD	MTD56	56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Pin Descriptions

Pin Names	Description			
OEAB	A-to-B Output Enable (Active LOW)			
OEBA	B-to-A Output Enable (Active LOW)			
CEAB	A-to-B Clock Enable (Active LOW)			
CEBA	B-to-A Clock Enable (Active LOW)			
LEAB	A-to-B Latch Enable (Transparent HIGH)			
LEBA	B-to-A Latch Enable (Transparent HIGH)			
V _{REF}	GTLP Reference Voltage			
CLKAB	A-to-B Clock			
CLKBA	B-to-A Clock			
A1-A17	A-to-B Data Inputs or B-to-A 3-STATE Data Outputs			
B1-B17	B-to-A Data Inputs or			
	A-to-B Open Drain Outputs			
CLKIN	B-to-A Buffered Clock Output			
CLKOUT	GTLP Buffered Clock Output of CLKAB			

Connection Diagram



Functional Description

The GTLP16617 is a 17 bit registered transceiver containing D-type flip-flop, latch and transparent modes of operation for the data path and a GTLP translation of the CLKAB signal (CLKOUT). Data flow in each direction is controlled by the clock enables (CEAB and CEBA), latch enables (LEAB and LEBA), clock (CLKAB and CLKBA) and output enables (OEAB and OEBA). The clock enables (CEAB and CEBA) enable all 17 data bits. The output enables (OEAB and OEBA) control both the 17 bits of data and the CLKOUT/CLKIN buffered clock paths and the OEAB is synchronous with the CLKAB signal. The OEBA can not be synchronous since we are passing the clock through the device with data and we would need to generate the CLKBA signal elsewhere. It should also be noted that the OEAB register is controlled by CLKAB only, and is also not inhibited by the OEAB signal.

For A-to-B data flow, when $\overline{\text{CEAB}}$ is LOW, the device operates on the LOW-to-HIGH transition of CLKAB for the flip-flop and on the HIGH-to-LOW transition of LEAB for the latch path. That is, if $\overline{\text{CEAB}}$ is LOW and LEAB is LOW the A data is latched regardless as to the state of CLKAB (HIGH or LOW) and if LEAB is HIGH the device is in transparent mode. When $\overline{\text{OEAB}}$ is registered LOW the outputs are active. When $\overline{\text{OEAB}}$ is registered HIGH the outputs are HIGH impedance. The data flow of B-to-A is similar except that $\overline{\text{CEBA}}$, $\overline{\text{OEBA}}$, LEBA and CLKBA are used.

Truth Table

(Note 1)

Inputs				Output	Mode	
CEAB	OEAB (Note 2)	LEAB	CLKAB	Α	В	
Х	Н	Χ	1	Χ	Z (Note 3)	Latched storage
L	L	L	Н	Χ	B ₀ (Note 4)	of A data
L	L	L	L	Χ	(Note 5)	
Х	L	Н	X	L	L	Transparent
X	L	Н	X	Н	Н	
L	L	L	1	L	L	Clocked storage
L	L	L	1	Н	Н	of A data
Н	L	L	X	Х	B ₀ (Note 5)	Clock inhibit

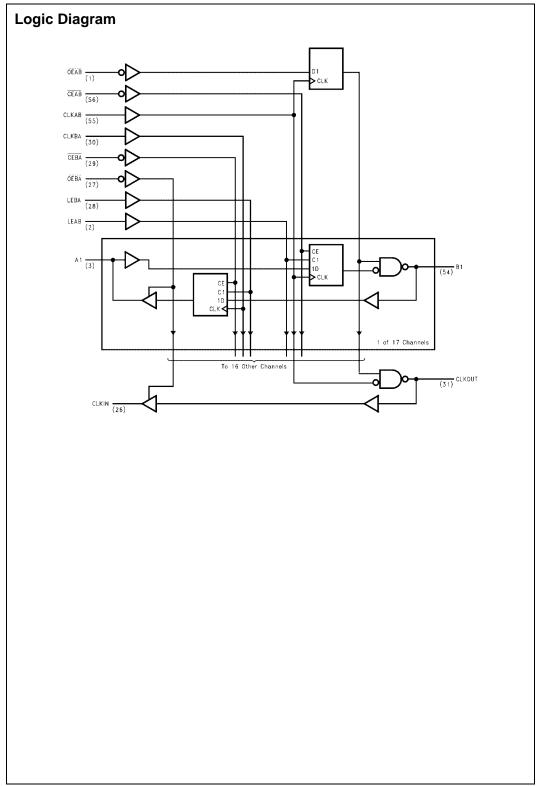
Note 1: A-to-B data flow is shown. B-to-A data flow is similar but uses $\overline{\text{OEBA}}$, LEBA, CLKBA, $\overline{\text{CEBA}}$.

Note 2: LH edge on CLKAB is required when changing the input on OEAB pin.

Note 3: OEAB met set-up time prior to CLKAB LH transition

Note 4: Output level before the indicated steady state input conditions were established, provided CLKAB was HIGH prior to LEAB going LOW.

Note 5: Output level before the indicated steady state input conditions were established.



Absolute Maximum Ratings(Note 6)

Recommended Operating Conditions (Note 8)

Supply Voltage (V_{CC}) -0.5V to +7.0V DC Input Voltage (V_{I}) -0.5V to +7.0V

DC Input Voltage (V_I) -0.5V to +7.0 DC Output Voltage (V_O)

Outputs 3-STATE -0.5V to +7.0V Outputs Active (Note 7) -0.5V to V_{CC} + 0.5V

DC Output Sink Current into

A Port I_{OL} 64 mA

DC Output Source Current from

A Port I_{OH} –64 mA

DC Output Sink Current

into B Port in the LOW State, I_{OL} 80 mA DC Input Diode Current (I_{IK})

 $V_I < 0V$ –50 mA

DC Output Diode Current (I_{OK})

 $\begin{array}{c} \rm V_O < 0V & -50 \; mA \\ \\ \rm V_O > V_{CC} & +50 \; mA \\ \\ \rm ESD \; Rating & >2000V \end{array}$

Storage Temperature (T_{STG}) $-65^{\circ}C$ to $+150^{\circ}C$

Supply Voltage V_{CC}

 $\begin{array}{c} V_{CC} & 3.15 \text{V to } 3.45 \text{V} \\ V_{CCQ} & 4.75 \text{V to } 5.25 \text{V} \\ \text{Bus Termination Voltage (V}_{TT}) \text{ GTLP} & 1.35 \text{V to } 1.65 \text{V} \\ \end{array}$

Input Voltage (V_I)

on A Port and Control Pins 0.0V to 5.5V

HIGH Level Output Current (I_{OH})

A Port –32 mA

LOW Level Output Current (I_{OL})

A Port +32 mA B Port +34 mA

Operating Temperature (T_A) $-40^{\circ}\text{C} \text{ to } +85^{\circ}\text{C}$

Note 6: The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum rating. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 7: I_O Absolute Maximum Rating must be observed.

Note 8: Unused inputs must be held HIGH or LOW.

DC Electrical Characteristics

Over Recommended Operating Free-Air Temperature Range, V_{REF} = 1.0V (Unless Otherwise Noted).

	Symbol	Test Condition	s	Min	Typ (Note 9)	Max	Units	
V _{IH}	B Port			V _{REF} +0.1		V _{TT}	V	
	Others			2.0			V	
V _{IL}	B Port			0.0		V _{REF} -0.2	V	
	Others					0.8	V	
V_{REF}	GTLP				1.0		V	
	GTL				0.8		V	
V _{IK}		$V_{CC} = 3.15V,$ $V_{CCQ} = 4.75V$	I _I = -18 mA			-1.2	V	
V _{OH}	A Port	V _{CC} , V _{CCQ} = Min to Max (Note 10)	$I_{OH} = -100 \mu A$	V _{CC} -0.2				
		V _{CC} = 3.15V	$I_{OH} = -8 \text{ mA}$	2.4			V	
		V _{CCQ} = 4.75V	$I_{OH} = -32 \text{ mA}$	2.0				
V _{OL}	A Port	V _{CC} , V _{CCQ} = Min to Max (Note 10)	$I_{OL} = 100 \mu A$			0.2	٧	
		V _{CC} = 3.15V	$I_{OL} = 32 \text{ mA}$			0.5		
		V _{CCQ} = 4.75V						
	B Port	V _{CC} = 3.15V V _{CCQ} = 4.75V	$I_{OL} = 34 \text{ mA}$			0.65	V	
l _l	Control Pins	V _{CC} , V _{CCQ} = 0 or Max	$V_I = 5.5V$ or $0V$			±10	μА	
	A Port	V _{CC} = 3.45V	$V_{I} = 5.5V$			20		
		V _{CCQ} = 5.25V	$V_I = V_{CC}$			1	μΑ	
			$V_I = 0$			-30		
	B Port	V _{CC} = 3.45V	$V_I = V_{CCQ}$			5		
		V _{CCQ} = 5.25V	$V_I = 0$			-5	μА	
l _{OFF}	A Port and Control Pins	$V_{CC} = V_{CCQ} = 0$	V_I or $V_O = 0$ to 4.5V			100	μΑ	
I _{I(hold)}	A Port	V _{CC} = 3.15V,	V _I = 0.8V	75				
		V _{CCQ} = 4.75V	$V_{I} = 2.0V$	-20			μΑ	
lozh	A Port	V _{CC} = 3.45V,	$V_0 = 3.45V$			1	μΑ	
	B Port	V _{CCQ} = 5.25V	V _O = 1.5V			5		
I _{OZL}	A Port	V _{CC} = 3.45V,	V _O = 0			-20		
	B Port	V _{CCQ} = 5.25V	V _O = 0.65V			-10	μΑ	

DC Electrical Characteristics (Continued)

Symbol		Test Conditions		Min	Typ (Note 9)	Max	Units
I _{CCQ}	A or B	V _{CC} = 3.45V,	Outputs HIGH		30	40	
(V _{CCQ})	Ports	$V_{CCQ} = 5.25V$,	Outputs LOW		30	40	mA
		$I_O = 0$,					IIIA
		$V_I = V_{CCQ}$ or GND	Outputs Disabled		30	40	
I _{CC}	A or B	$V_{CC} = 3.45V, V_{CCQ} = 5.25V, I_{O} = 0,$	Outputs HIGH		0	1	
(V _{CC})	Ports		Outputs LOW		0	1	mA
		$V_I = V_{CCQ}$ or GND	Outputs Disabled		0	1	
ΔI_{CC}	A Port and	V _{CC} = 3.45V,	One Input at 2.7V		0	1	
(Note 11)	Control Pins	$V_{CCQ} = 5.25V$,					mA
		A or Control Inputs at					IIIA
		V _{CC} or GND					
C _{IN}	Control Pins		$V_I = V_{CCQ}$ or 0		8		
C _{I/O}	A Port		$V_I = V_{CCQ}$ or 0		9		pF
C _{I/O}	B Port		$V_I = V_{CCQ}$ or 0		6		

Note 9: All typical values are at $V_{CC}=3.3V,\ V_{CCQ}=5.0V,$ and $T_A=25^{\circ}C.$

Note 10: For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions.

Note 11: This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

AC Operating Requirements

Over recommended ranges of supply voltage and operating free-air temperature, $V_{REF} = 1.0V$ (unless otherwise noted).

Symbol			Min	Max	Unit
f _{MAX}	Maximum Clock Frequency		175		MHz
t _W	Pulse Duration	LEAB or LEBA HIGH	3.0		
		CLKAB or CLKBA HIGH or LOW	3.2		ns
t _S	Setup Time	A before CLKAB↑	0.5		
		OEAB before CLKAB↑	1.5		
		B before CLKBA↑	3.1		
		A before LEAB \downarrow	1.3		ns
		B before LEBA↓	3.7		
		CEAB before CLKAB↑	0.7		
		CEBA before CLKBA↑	1.0		
t _H	Hold Time	A after CLKAB↑	1.5		
		OEAB after CLKAB↑	1.0		
		B after CLKBA↑	0.0		
		A after LEAB↓	0.5		ns
		B after LEBA↓	0.0		
		CEAB after CLKAB↑	1.5		
		CEBA after CLKBA↑	1.7		

AC Electrical Characteristics

Over recommended range of supply voltage and operating free-air temperature, $V_{REF} = 1.0V$ (unless otherwise noted). $C_L = 30$ pF for B Port and $C_L = 50$ pF for A Port.

Symbol	From	То	Min	Тур	Max	Unit
	(Input)	(Output)		(Note 12)		
PLH	А	В	1.0	4.3	6.5	
PHL			1.0	5.0	8.2	ns
PLH	LEAB	В	1.8	4.5	6.7	
PHL			1.5	5.3	8.7	ns
PLH	CLKAB	В	1.8	4.6	6.7	
PHL			1.5	5.4	8.7	ns
PLH	CLKAB	CLKOUT	3.0	6.2	10.0	
PHL			3.0	5.7	10.0	ns
PLH	OEAB	В	1.6	4.4	8.0	
PHL	(CLKAB) (Note 13)		1.3	6.1	9.8	ns
SKEW	B (Note 14)	CLKOUT	0		2	ns
RISE	Transition time, B of	outputs (20% to 80%)		2.6		
FALL	Transition time, B of	outputs (20% to 80%)		2.6		ns
PLH	В	A	2.0	5.6	8.2	
PHL			1.4	5.0	7.2	ns
PLH	LEBA	A	2.1	4.2	6.3	
PHL			1.9	3.3	5.0	ns
PLH	CLKBA	А	2.3	4.4	6.8	
PHL			2.1	3.5	5.2	ns
PLH	CLKOUT	CLKIN	3.0	6.0	10.0	
PHL			3.0	6.43	10.0	ns
PZH ^{, †} PZL	OEBA	A or CLKIN	1.5	5.0	6.4	
PHZ, t _{PLZ}			1.4	3.9	8.0	ns

Note 12: All typical values are at V $_{CC}$ = 3.3V, V $_{CCQ}$ = 5.0V, and T $_{A}$ = 25 $^{\circ}C.$

Note 13: Three-state delays are actually synchronous with CLKAB

Note 14: Skew is defined as the absolute value of the difference between the actual propagation delays for the CLKOUT pin and any B output transition when measured with reference to CLKAB1. This guarantees the relationship between B output data and CLKOUT such that data is coincident or ahead of CLKOUT. This specification is guaranteed but not tested.

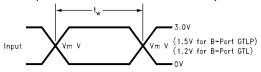
Test Circuits and Timing Waveforms

From Output $C_L = 50 \text{ pF}$ $C_L \text{ includes probes and jig capacitance.}$ $C_L \text{ includes probes}$ $C_L \text{ includes probes and jig capacitance.}$

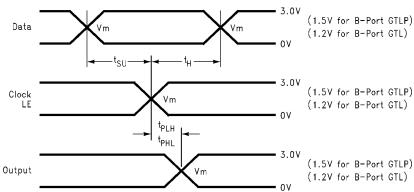
Test Circuit for B Outputs 1.5V (GTLP) 1.2V (GTL) From Output Under Test 30 pF

 C_{L} includes probes and jig capacitance. For B Port outputs, $\text{C}_{L}=30~\text{pF}$ is used for worst case edge rate.

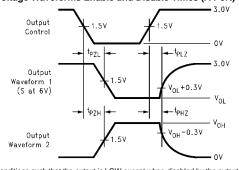
Voltage Waveforms Pulse Duration (Vm = 1.5V for A Port and 1.0V for B Port)



Voltage Waveforms Propagation Delay and Setup and Hold Times (Vm = 1.5V for A Port and 1.0V for B Port)

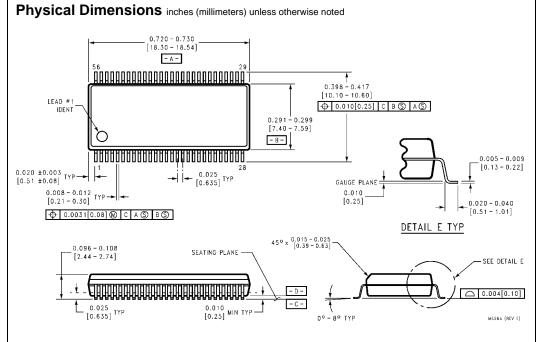


Voltage Waveforms Enable and Disable Times (A Port)

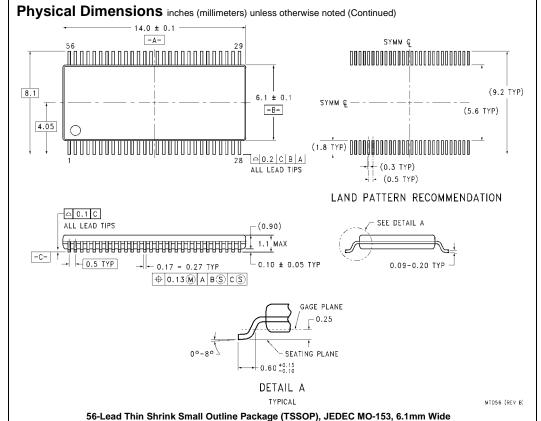


Waveform 1 is for an output with internal conditions such that the output is LOW except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is HIGH except when disabled by the output control. All input pulses have the following characteristics: frequency = 10 MHz, $t_r = t_f = 2$ ns, $Z_O = 50\Omega$. The outputs are measured one at a time with one transition

All input pulses have the following characteristics: frequency = 10 MHz, $t_r = t_f = 2$ ns, $Z_O = 50\Omega$. The outputs are measured one at a time with one transition per measurement.



56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300 Wide Package Number MS56A



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Package Number MTD56

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